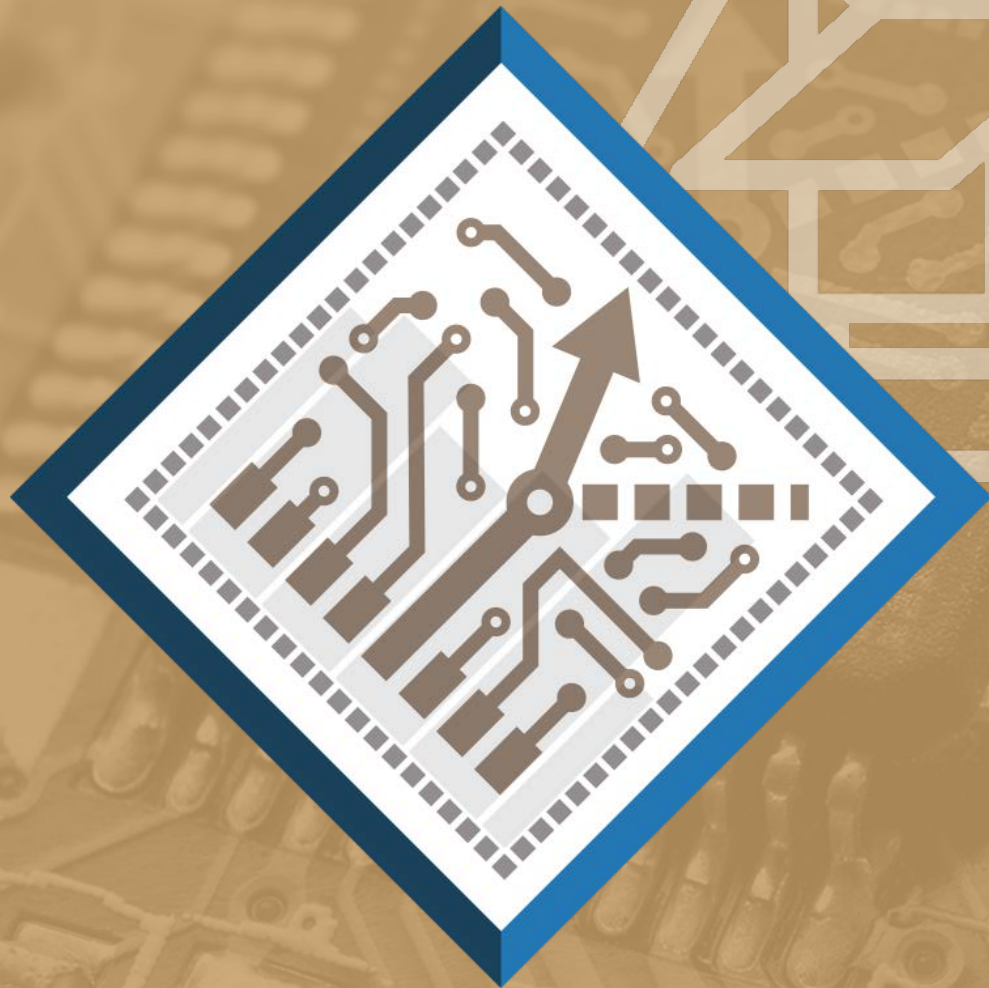




LINTON SALMON

PROGRAM MANAGER
DARPA/ MTO



3D MONOLITHIC SYSTEM ON A CHIP (3DSOC)

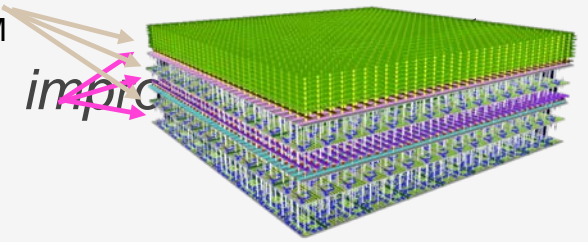
3DSOC PROGRAM

GOALS AND METRICS

Program Goal

Develop novel monolithic 3D fabrication technologies enable new architectures to drive a >50X SoC performance at power

12 layers of ReRAM interspersed with 5 layers of CNFET logic



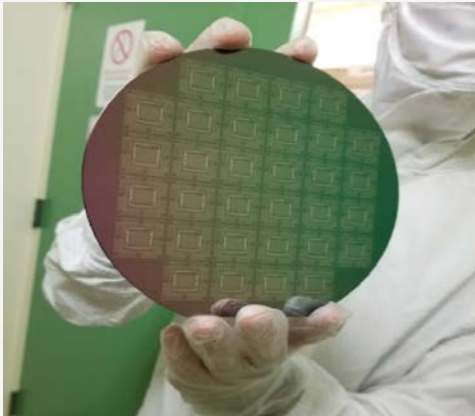
Program Metrics

- 3DSoc technology capability of >50X Vs. 2D 7nm Performance at Power (PaP)
 - Interconnect densities > 9M interconnects/mm² between 3D layers
 - Interconnect bandwidth > 45Tb/s between 3D layers
 - On-die memory access energy < 2pJ/bit
- Yield > 30% for full 3DSoc designs
- Successful use of EDA flow for a > 500M gate/4GB memory 3DSoc design
- Capability to be fabricated as an on-demand foundry service for multiple DoD and commercial customers using a U.S. fabrication facility

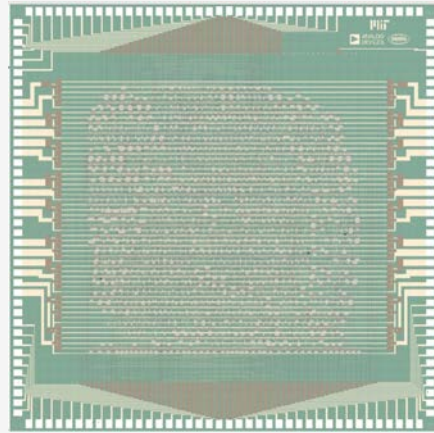
3DSOC PROGRAM

MAJOR ACCOMPLISHMENTS

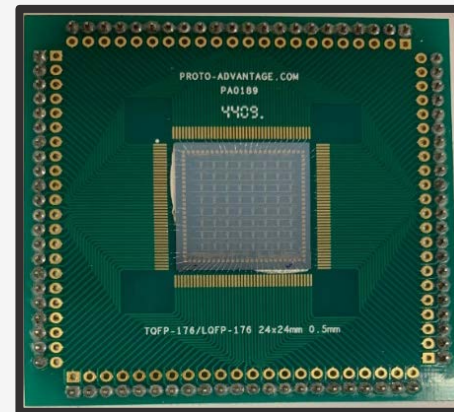
SkyWater 3DSoC Test Wafer



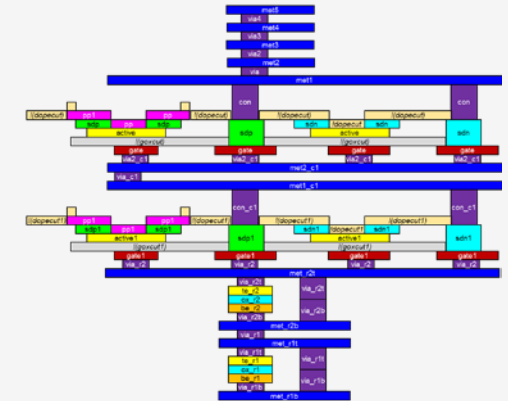
MIT CNFET ASIC



MIT Multi-Level CNFET Sensor



Calibrated Process Design Kit (PDK)



- Carbon Nanotube FETs (CNFETs) and Resistance Memory (RRAM) fabricated at SkyWater Technology Foundry
- Key CNFET building blocks demonstrated at MIT
 - Complex digital ASIC fabricated with CNFETs
 - Multi-level CNFET demonstrated
- Calibrated Process Design Kit (PDK) developed and delivered to alpha design teams

3DSOC

PERFORMERS

MIT

PI: Max Shulaker (MIT)

Co-PI: Mark Nelson (SkyWater)

*Co-PIs: Subhasish Mitra & Simon Wong
(Stanford)*

CNFET development

3DSoc Fabrication Foundry

System Simulation & RRAM Development

GA Tech

PI: Sung Kyu Lim (GA Tech)

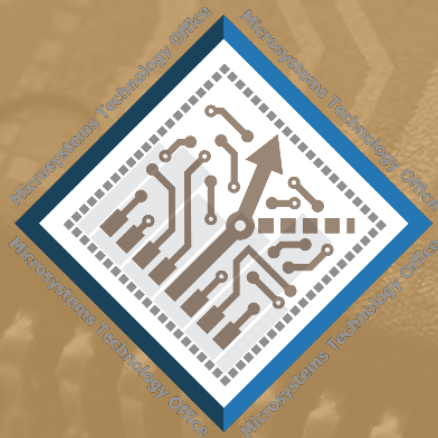
Co-PI: Saibal Mukhopadhyay (GA Tech)

Co-PI: Krishnendu Chakrabarty (Duke)

3DSoc Design Tool Development

3DSoc Memory Design Development

3DSoc Design for Testability



ERI ELECTRONICS RESURGENCE INITIATIVE

S U M M I T

2019 | Detroit, MI | **July 15 - 17**